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## **Schedule of Accreditation**

	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibrati	ion –	Electri	ical Quantities - DC and	LF			ם ישר ותדר נמוך	ביול – גדלים חשמליים - זר
1       A         2       A         3       A         4       A         5       A         6       A         7       A         8       A         9       A         10       A         11       A         12       A         13       A         14       A         15       A         16       A         17       A         18       A	A A A A A A A A A A A A A A A A A A A	P P P P P P P P T T T T T	DC Voltage, Sources	ארם ישר מחוללי מתח	(0.1 μV to 115 mV] (115 mV to 0.9 V] (0.9 V to 1.1 V] (1.1 V to 9 V] (9 V to 11 V] (11 V to 18 V] (18 V to 19.5 V] (19.5 V to 20 V] (20 V to 90 V] 90 V to 110 V] (110 V to 900 V] (900 V to 1.1 kV] 0.1 μV to 200 μV] (200 μV to 85 mV] (85 mV to 0.9 V] (0.9 V to 20 V] (20 V to 90 V]	$\begin{array}{c} 2 \ \mu V \\ 6 \ \mu V/V + 0.4 \ \mu V \\ 4 \ \mu V/V \\ 6 \ \mu V/V + 20 \ \mu V \\ 3.2 \ \mu V/V \\ 6 \ \mu V/V + 20 \ \mu V \\ 3 \ \mu V/V \\ 6 \ \mu V/V + 20 \ \mu V \\ 10 \ \mu V/V + 40 \ \mu V \\ 4 \ \mu V/V \\ 15 \ \mu V/V \\ 7 \ \mu V/V + 0.1 \ \mu V \\ 6 \ \mu V/V + 0.4 \ \mu V \\ 6 \ \mu V/V + 0.4 \ \mu V \\ 6 \ \mu V/V + 20 \ \mu V \\ 10 \ \mu V/V + 20 \ \mu V \\ 15 \ \mu V/V \\ 4 \ \mu V/V + 0.4 \ \mu V \\ 6 \ \mu V/V + 20 \ \mu V \\ 10 \ \mu V/V + 20 \ \mu V \\ 10 \ \mu V/V + 40 \ \mu V \\ 15 \ \mu V/V \end{array}$	Portocal II MetCal MTS Automated Calibration Software Manufacturer instructions	Wavetek 9100 Datron 1281 Wavetek 4808 Wavetek 4912 Wavetek MTS 4950 Fluke 5520A Fluke 5720 A Fluke 734A

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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Calibra	ation –	Electr	ical Quantities - DC and	LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
19 20 21 22 23 24 25 26 27 28	A A A	P P P P P T T	DC Voltage, Measuring Instruments	זרם ישר מכשירי מדידת מתח	$\begin{array}{c} \pm 1 \text{ V} \\ \pm 1.018 \text{ V} \\ \pm 10 \text{ V} \\ \\ [0.4 \mu\text{V to } 200 \text{mV}] \\ (200 \text{mV to } 2 \text{V}] \\ (2 \text{V to } 20 \text{V}] \\ (20 \text{V to } 200 \text{V}] \\ (200 \text{V to } 1100 \text{V}] \\ (10 \text{mV to } 20 \text{mV}] \\ (20 \text{mV to } 200 \text{mV}] \\ (200 \text{mV to } 200 \text{mV}] \\ (200 \text{mV to } 200 \text{mV}] \\ (200 \text{mV to } 200 \text{V}] \\ (200 \text{V to } 200 \text{V}] \end{array}$	$3.4 \mu\text{V/V}$ $3 \mu\text{V/V}$ $2.5 \mu\text{V/V}$ $7 \mu\text{V/V} + 0.4 \mu\text{V}$ $5 \mu\text{V/V} + 0.8 \mu\text{V}$ $3 \mu\text{V/V} + 2.3 \mu\text{V}$ $5 \mu\text{V/V} + 39 \mu\text{V}$ $6 \mu\text{V/V} + 3.9 \text{mV}$ $0.84 \mu\text{V/V}$ $6.4 \mu\text{V/V}$ $0.18 \text{mV/V}$ $8.5 \text{mV/V}$	Portocal II MetCal MTS Automated Calibration Software Manufacturer instructions	Fluke 734A Wavetek 4912 Wavetek 4808 Fluke 5720 A Datron 1281 Wavetek MTS 4950 Fluke 5520A Wavetek 9100	
31	A	T			(200 V to 1100 V]	35 mV/V			
33 34 35 36	A A A A A	P;T P;T P;T P;T P;T	DC Current. Sources	זרם ישר, מחוללים	(10 nA to 200 μA] (200 μA to 0.9 mA] (0.9 mA to 1.1 mA] (1.1 mA to 2 mA] (2 mA to 9 mA] (9 mA to 11 mA]	25 $\mu$ A/A + 1 nA 25 $\mu$ A/A + 5 nA 19 $\mu$ A/A 25 $\mu$ A/A + 5 nA 25 $\mu$ A/A + 70 nA 19 $\mu$ A/A	Portocal II MetCal MTS Automated Calibration Software  Manufacturer instructions	Datron 1281 Current clamp Fluke 337	

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	ope Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration	n – Electr	ical Quantities - DC and	LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
38 A 39 A 40 A 41 A 42 A 43 A 44 A 45 A 46 A 47 A 48 A 49 A 50 A 51 A 52 A 53 A 54 A 55 A	P;T	DC Current, Measuring Instruments	לבד. זרם ישר, מכשירי מדידת זרם	(Does not include margins)  (11 mA to 20 mA] (20 mA to 90 mA] (90 mA to 110 mA] (110 mA to 200 mA] (200 mA to 0.9 A] (0.9 A to 1.1 A] (1.1 A to 2 A] (9 A to 11 A] (2 nA to 200 μA] (200 μA to 2 mA] (2 mA to 20 mA] (20 mA to 20 mA] (20 mA to 20 mA] (20 A to 10 A] (10 A to 20 A] (20 A to 32 A] (32 A to 105 A] (105 A to 160 A] (160 A to 525 A]	25 μA/A + 50 nA 50 μA/A + 1.3 μA 24 μA/A 50 μA/A + 1.3 μA 150 μA/A + 25 μA 71 μA/A 150 μA/A + 25 μA 67 μA/A 80 μA/A + 2 nA 33 μA/A + 8 nA 33 μA/A + 78 nA 33 μA/A + 1 μA 82 μA/A + 16 μA 30 μA/A+390 μA 0.55 mA/A + 4.5 mA 0.60 mA/A + 5.9 mA 0.55 mA/A + 47 mA	Protocal II MetCal MTS Automated Calibration Software  Manufacturer instructions	Standard resistors Datron 1281 Wavetek 9100 Wavetek 4808 Wavetek MTS 4950 Fluke 5520A Fluke 5720A Fluke 5725A Current Coils	

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Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electr	ical Quantities - DC and	LF	ביול – גדלים חשמליים - זרם ישר ותדר נמוך			
57	A	P			(525 A to 1000 A]	0.55 mA/A + 225 mA		
58	A	T			(2 A to 10 A]	$30~\mu A/A + 390~\mu A$		
59	A	T			(10 A to 20 A]	0.55  mA/A + 4.5  mA		
60	A	T			(20 A to 32 A]	0.60  mA/A + 1.18  mA		
61	A	T			(32 A to 105 A]	0.55  mA/A + 9.4  mA		
62	A	T			(105 A to 160 A]	0.60  mA/A + 5.9  mA		
63	A	T			(160 A to 525 A]	0.55  mA/A + 47  mA		
64	A	T			(525 A to 1000 A]	0.55 mA/A + 225 mA		
			AC Voltage,		(0.85 mV to 1.15 mV]		Portocal II	Datron 1281
65	A	P;T	Sources	מחוללים מתח	[18 Hz to 46.25 Hz]	$260\;\mu\text{V/V}$	MetCal	Wavetek MTS 4950
66	A	P;T			(46.25 Hz to 22 kHz]	2.6 mV/V	MTS Automated	
67	A	P;T			(22 kHz to 33 kHz]	2.7 mV/V	Calibration Software	
68	A	P;T			(33 kHz to 55 kHz]	3.5 mV/V	Manufacturer instructions	
69	A	P;T			(55 kHz to 110 kHz]	4.4  mV/V		
70	A	P;T			[450 kHz to 550 kHz]	8.1 mV/V		
					(1.15 mV to 8.5 mV]			
71	A	P;T			[10 Hz to 40 Hz]	$200~\mu\text{V/V}$		
72	A	P;T			(40 Hz to 100 Hz]	$190\;\mu\text{V/V}$		
73	A	P;T			(100 Hz to 10 kHz]	$170\;\mu\text{V/V}$		

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Calibra	ation –	Electri	cal Quantities - DC and LF	,	כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
74	A	P;T		(10 kHz to 30 kHz]	$370~\mu\text{V/V}$			
75	A	P;T		(30 kHz to 100 kHz]	$820~\mu V/V$			
				(8.5 mV to 11.5 mV]				
76	A	P;T		[20 Hz to 22 Hz]	$480\;\mu\text{V/V}$			
77	A	P;T		(22 Hz to 63.75 Hz]	$490~\mu\text{V/V}$			
78	A	P;T		(63.75 Hz to 1.1 kHz]	$480~\mu\text{V/V}$			
79	A	P;T		(1.1 kHz to 11 kHz]	$490~\mu\text{V/V}$			
80	A	P;T		(11 kHz to 22 kHz]	$500~\mu V/V$			
81	A	P;T		(22 kHz to 33 kHz]	570 μV/V			
82	A	P;T		(33 kHz to 55 kHz]	920 μV/V			
83	A	P;T		(55 kHz to 110 kHz]	1.1 mV/V			
				(11.5 mV to 85 mV]				
84	A	P;T		[10 Hz to 40 Hz]	$470~\mu\text{V/V}$			
85	A	P;T		(40 Hz to 100 Hz]	$460~\mu\text{V/V}$			
86	A	P;T		(100 Hz to 2 kHz]	$430\;\mu\text{V/V}$			
87	A	P;T		(2 kHz to 10 kHz]	$430\;\mu\text{V/V}$			
88	A	P;T		(10 kHz to 30 kHz]	$780~\mu\text{V/V}$			
89	A	P;T		(30 kHz to 100 kHz]	1.5 mV/V			

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Calibra	ation –	Electri	cal Quantities - DC and LF	. ,		רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				(85 mV to 115 mV]			
90	A	P;T		[18 Hz to 63.75 Hz]	$220~\mu\text{V/V}$		
91	A	P;T		[270 Hz to 440 Hz]	$360~\mu V/V$		
92	A	P;T		[0.94 kHz to 1.1 kHz]	$180~\mu\text{V/V}$		
93	A	P;T		[9 kHz to 11 kHz]	$200~\mu\text{V/V}$		
94	A	P;T		[18 kHz to 22 kHz]	$220~\mu\text{V/V}$		
95	A	P;T		[27 kHz to 33 kHz]	$310~\mu V/V$		
96	A	P;T		[45 kHz to 55 kHz]	$320~\mu\text{V/V}$		
97	A	P;T		[90 kHz to 110 kHz]	$550~\mu V/V$		
				(115 mV to 200 mV]			
98	A	P;T		[10 Hz to 40 Hz]	$240~\mu\text{V/V}$		
99	A	P;T		(40 Hz to 100 Hz]	$320~\mu\text{V/V}$		
100	A	P		(100 Hz to 2 kHz]	$300~\mu\text{V/V}$		
101	A	P		(2 kHz to 10 kHz]	$310~\mu\text{V/V}$		
102	Α	P		(10 kHz to 30 kHz]	$600~\mu V/V$		
103	A	P		(30 kHz to 100 kHz]	1.1 mV/V		
				(200 mV to 0.9 V]			
104	A	P		[40 Hz to 100 Hz]	290 μV/V		
105	A	P		(100 Hz to 2 kHz]	260 μV/V		

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Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
ation –	Electri	cal Quantities - DC and LF	, <u>, , , , , , , , , , , , , , , , , , </u>	יול – גדלים חשמליים - זרם ישר ותדר נמוך		
A	P		(2 kHz to 10 kHz]	290 μV/V		
Α	P		(10 kHz to 30 kHz]	570 μV/V		
A	P		(30 kHz to 100 kHz]	1.1 mV/V		
			(0.9 V to 1.1 V]			
A	P;T		[9 Hz to 33 Hz]	1200 μV/V		
Α	P;T		(33 kHz to 270 kHz]	2600 μV/V		
A	P;T		(270 kHz to 330 kHz]	3700 μV/V		
A	P;T		(450 kHz to 550 kHz]	7300 µV/V		
A	P;T		(0.9 MHz to 1.1 MHz]	7400 μV/V		
			(1.1 V to 2 V]			
A	P;T		[40 Hz to 100 Hz]	440 μV/V		
A	P;T		(100 Hz to 2 kHz]	320 μV/V		
A	P;T		(2 kHz to 10 kHz]	380 μV/V		
Α	P;T		(10 kHz to 30 kHz]	600 μV/V		
A	P;T		(30 kHz to 100 kHz]	1.8 mV/V		
A	P;T		(100 kHz to 300 kHz]	15 mV/V		
A	P;T		(300 kHz to 1 MHz]	127 mV/V		
A	P;T		(2 V to 9 V] [40 Hz to 100 Hz]	210 μV/V		
	AAAAAAAAAAAAAAAAAAAAAAAAAAAAAAAAAAAAAA	Type           ation - Electri           A         P           A         P           A         P;T           A         P;T	A	Including margins   (Does not include margins)	Type	Type

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Calibre	ation –	Electri	cal Quantities - DC and LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך		
122	A	P;T		(100 Hz to 2 kHz]	180 μV/V		
123	A	P;T		(2 kHz to 10 kHz]	$210~\mu\text{V/V}$		
124	A	P;T		(10 kHz to 30 kHz]	$350~\mu\text{V/V}$		
125	A	P;T		(30 kHz to 100 kHz]	$840~\mu\text{V/V}$		
126	A	P;T		(100 kHz to 300 kHz]	6 mV/V		
127	A	P;T		(300 kHz to 1 MHz]	37 mV/V		
				(9 V to 11 V]			
128	A	P;T		[9 Hz to 22 kHz]	$370~\mu\text{V/V}$		
129	A	P;T		(33 kHz to 55 kHz]	$820~\mu\text{V/V}$		
130	A	P;T		(90 kHz to 110 kHz]	$820~\mu\text{V/V}$		
131	A	P;T		(270 kHz to 330 kHz]	1.2 mV/V		
132	A	P;T		(450 kHz to 550 kHz]	2.3 mV/V		
133	A	P;T		(0.9 MHz to 1.1 MHz]	2.5 mV/V		
				(11 V to 18 V]			
134	A	P;T		[10 Hz to 40 Hz]	$210~\mu\text{V/V}$		
135	A	P;T		(40 Hz to 100 Hz]	$190~\mu\text{V/V}$		
136	A	P;T		(100 Hz to 2 kHz]	$170~\mu\text{V/V}$		
137	A	P;T		(2 kHz to 10 kHz]	$190~\mu\text{V/V}$		
138	A	P;T		(10 kHz to 30 kHz]	$320~\mu V/V$		

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Calibro	ation –	Electri	cal Quantities - DC and LF		יול – גדלים חשמליים - זרם ישר ותדר נמוך		
139	A	P;T		(30 kHz to 100 kHz]	$710~\mu V/V$		
140	A	P;T		(100 kHz to 300 kHz]	5 mV/V		
141	A	P;T		(300 kHz to 1 MHz]	24 mV/V		
				(18 V to 19.5 V]			
142	A	P;T		[100 kHz to 1.1 MHz]	520 μV/V		
				(19.5 V to 90 V]			
143	A	P;T		[10 Hz to 40 Hz]	$240~\mu\text{V/V}$		
144	A	P;T		(40 Hz to 100 Hz]	$200~\mu\text{V/V}$		
145	A	P;T		(100 Hz to 2 kHz]	$180~\mu\text{V/V}$		
146	A	P;T		(2 kHz to 10 kHz]	$200~\mu\text{V/V}$		
147	A	P;T		(10 kHz to 30 kHz]	$340~\mu\text{V/V}$		
148	A	P;T		(30 kHz to 100 kHz]	$830 \mu V/V$		
149	A	P;T		(100 kHz to 300 kHz]	6 mV/V		
150	A	P;T		(300 kHz to 1 MHz]	37 mV/V		
				(90 V to 110 V]			
151	A	P;T		[9 Hz to 33 Hz]	64 μV/V		
152	A	P;T		(33 Hz to 63.75 Hz]	57 μV/V		
153	A	P;T		(63.75 Hz to 22 kHz]	$42~\mu V/V$		
154	A	P;T		(22 kHz to 33 kHz]	$46~\mu\text{V/V}$		
155	A	P;T		(33 kHz to 55 kHz]	$58~\mu V/V$		
156	A	P;T		(55 kHz to 110 kHz]	$100~\mu V/V$		

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Calibr	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				(110 V to 200 V]			
157	Α	P;T		[10 Hz to 40 Hz]	$320~\mu\text{V/V}$		
158	A	P;T		(40 Hz to 100 Hz]	$280\;\mu\text{V/V}$		
159	Α	P;T		(100 Hz to 2 kHz]	$280\;\mu\text{V/V}$		
160	Α	P;T		(2 kHz to 10 kHz]	280 μV/V		
161	Α	P;T		(10 kHz to 30 kHz]	770 μV/V		
162	A	P;T		(30 kHz to 100 kHz]	1.5 mV/V		
				(200 V to 600 V]			
163	A	P;T		[10 Hz to 40 Hz]	240 μV/V		
164	A	P;T		(40 Hz to 10 kHz]	210 μV/V		
165	A	P;T		(10 kHz to 30 kHz]	430 μV/V		
166	A	P;T		(30 kHz to 100 kHz]	900 μV/V		
				(600 V to 800 V]			
167	Α	P;T		45 kHz to 55 kHz	180 μV/V		
				(800 V to 900 V]			
168	A	P;T		[10 Hz to 40 Hz]	230 μV/V		
169	Α	P;T		(40 Hz to 10 kHz]	200 μV/V		
170	Α	P;T		(10 kHz to 30 kHz]	420 μV/V		
171	A	P;T		(30 kHz to 100 kHz]	740 μV/V		
				(900 V to 1100 V]			
172	A	P;T		[46.25 Hz to 1.1 kHz]	59 μV/V		

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Calibr	ation –	Electr	ical Quantities - DC and	LF			ים ישר ותדר נמוך	כיול – גדלים חשמליים - זו
173	A	P;T			(1.1 kHz to 11 kHz]	66 μV/V		
174	A	P;T			(11 kHz to 22 kHz]	$74~\mu V/V$		
175	A	P;T			(22 kHz to 33 kHz]	110 μV/V		
176 177 178 179 180 181 182 183 184 185 186 187	A A A A	P;T	AC Voltage. Measuring Instruments	מתח חילופין מכשירי מדידת מתח	(0.9 mV to 2 mV)  (10 Hz to 330 Hz)  (0.33 kHz to 10 kHz)  (10 kHz to 33 kHz)  (33 kHz to 100 kHz)  (100 kHz to 330 kHz)  (330 kHz to 1 MHz)  (2 mV to 20 mV)  (10 Hz to 30 Hz)  (32 Hz to 300 Hz)  (10 kHz to 33 kHz)  (33 kHz to 10 kHz)  (10 kHz to 33 kHz)  (31 kHz to 100 kHz)  (32 kHz to 100 kHz)  (33 kHz to 100 kHz)  (34 kHz to 100 kHz)  (35 kHz to 1 MHz)  (36 kHz to 31 kHz)  (37 kHz to 31 kHz)  (37 kHz to 31 kHz)  (38 kHz to 31 kHz)	4.7 mV/V 4.2 mV/V 4.8 mV/V 9.6 mV/V 9.7 mV/V 19 mV/V 560 μV/V 550 μV/V 610 μV/V 770 μV/V 1.4 mV/V 2.7 mV/V	Protocal II MetCal MTS Automated Calibration Software Manufacturer instructions	Datron 1281 Wavetek 9100 Wavetek 4808 Wavetek MTS 4950 Fluke 5520A Fluke 5720A

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ition –	Electri	cal Quantities - DC and LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך		
191	A	P;T		(330 Hz to 10 kHz]	74 μV/V		
192	A	P;T		(10 Hz to 33 kHz]	$230~\mu\text{V/V}$		
193	A	P;T		(33 kHz to 100 kHz]	$450~\mu\text{V/V}$		
194	A	P;T		(100 kHz to 330 kHz]	$990~\mu\text{V/V}$		
195	A	P;T		(330 kHz to 1 MHz]	2.1 mV/V		
				(200 mV to 2 V]			
196	A	P;T		[10 Hz to 31 Hz]	$82~\mu V/V$		
197	A	P;T		(32 Hz to 330 Hz]	$49~\mu\text{V/V}$		
198	A	P;T		(330 Hz to 33 kHz]	$41~\mu V/V$		
199	A	P;T		(33 kHz to 100 kHz]	$79~\mu V/V$		
200	A	P;T		(100 kHz to 330 kHz]	$340~\mu\text{V/V}$		
201	A	P;T		(330 kHz to 1 MHz]	2 mV/V		
				(2 V to 20 V]			
202	A	P;T		[10 Hz to 31 Hz]	$82~\mu V/V$		
203	A	P;T		(32 Hz to 330 Hz]	$56\mu V/V$		
204	A	P;T		(330 Hz to 10 kHz]	$8 \ \mu V/V$		
205	A	P;T		(10 Hz to 33 kHz]	$41~\mu V/V$		
206	A	P;T		(33 kHz to 100 kHz]	$75 \mu V/V$		
207	A	P;T		(100 kHz to 330 kHz]	$240~\mu\text{V/V}$		
208	A	P;T		(330 kHz to 1 MHz	1.3 mV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשרח למספר הנספח ומספרה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשרח למספר הנספח למספר הנספר הנספח למספר הנספח למספר הנספר הנספר הנספר הנספח למספר הנספר הנספר

## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ution —	Electr	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
					(20 V to 200 V]			
209	A	P;T			[10 Hz to 31 Hz]	91 μV/V		
210	A	P;T			(32 Hz to 330 Hz]	$56 \mu V/V$		
211	A	P;T			(330 Hz to 10 kHz]	$8\;\mu V/V$		
212	A	P;T			(10 kHz to 33 kHz]	$50~\mu V/V$		
213	A	P;T			(33 kHz to 100 kHz]	$120~\mu V/V$		
					(200 V to 1100 V]			
214	A	P;T			(45 Hz to 3.3 kHz]	$89 \mu V/V$		
215	A	P;T			(3.3 kHz to 10 kHz]	$120~\mu V/V$		
216	A	P;T			(10 kHz to 33 kHz]	$130~\mu V/V$		
					200 V to 750 V			
217	A	P;T			33 kHz to 100 kHz	360 μV/V		
			AC Current	,	(10 μA to 90 μA]		Portocal II	Datron 1281
218	A	P;T	Sources	מחוללי זרם	[10 Hz to 1 kHz]	860 μΑ/Α	MetCal	Wavetek MTS 4950
219	A	P;T			(1 kHz to 5 kHz]	1.5 mA/A	MTS	Fluke 337
					(90 μA to 110 μA]		Automated	
220	A	P;T			[9 Hz to 22 Hz]	130 μΑ/Α		
221	A	P;T			(22 Hz to 33 Hz]	120 μΑ/Α	Calibration Software Manufacturer instructions	
222	A	P;T			(33 Hz to 1.1 kHz]	99 μΑ/Α	ivianutacturer instructions	
223	A	P;T			(1.1 kHz to 5.5 kHz]	160 μΑ/Α		
								1

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				(110 μA to 200 μA]			
224	A	P;T		[10 Hz to 1 kHz]	510 μΑ/Α		
225	A	P;T		(1 kHz to 5 kHz]	640 μA/A		
				(200 µA to 0.9 mA]			
226	A	P;T		[10 Hz to 1 kHz]	830 μΑ/Α		
227	A	P;T		[1 kH]	860 μA/A		
228	A	P;T		(1 kHz to 5 kHz]	1.5 mA/A		
				(0.9 mA to 1.1 mA]			
229	A	P;T		[9 Hz to 22 Hz]	120 μA/A		
230	A	P;T		(22 Hz to 33 Hz]	110 μA/A		
231	A	P;T		(33 Hz to 1.1 kHz]	90 μΑ/Α		
232	A	P;T		(1.1 kHz to 5.5 kHz]	140 μA/A		
				(1.1 mA to 2 mA]			
233	A	P;T		[10 Hz to 1 kHz]	590 μA/A		
234	A	P;T		[1 kH]	600 μA/A		
235	A	P;T		(1 kHz to 5 kHz]	830 μΑ/Α		
				(2 mA to 9 mA]			
236	A	P;T		[10 Hz to 1 kHz]	590 μA/A		
237	A	P;T		(1 kHz to 5 kHz]	830 μA/A		
				(9 mA to 11 mA]			
238	A	P;T		[9 Hz to 22 Hz]	120 μΑ/Α		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibra	ation –	Electri	cal Quantities - DC and LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
239	A	P;T		(22 Hz to 33 Hz]	100 μΑ/Α			
240	A	P;T		(33 Hz to 1.1 kHz]	85 μΑ/Α			
241	A	P;T		(1.1 kHz to 5.5 kHz]	130 μΑ/Α			
				(11 mA to 20 mA]				
242	Α	P;T		(10 Hz to 1 kHz]	510 μΑ/Α			
243	A	P;T		[1 kHz to 5 kHz]	640 μA/A			
				(20 mA to 90 mA]				
244	A	P;T		[10 Hz to 55 Hz]	860 μΑ/Α			
245	A	P;T		(300 Hz to 1 kHz]	830 μΑ/Α			
246	Α	P;T		(1 kHz to 5 kHz]	1.5 mA/A			
				(90 mA to 110 mA]				
247	Α	P;T		[9 Hz to 22 Hz]	120 μΑ/Α			
248	Α	P;T		(22 Hz to 33 Hz]	100 μΑ/Α			
249	A	P;T		(33 Hz to 1.1kHz]	85 μΑ/Α			
250	A	P;T		(1.1 kHz to 5.5 kHz]	510 μΑ/Α			
				(110 mA to 200 mA]				
251	A	P;T		[10 Hz to 55 Hz]	640 μA/A			
252	Α	P;T		(300 Hz to 1 kHz]	1.7 mA/A			
253	A	P;T		(1 kHz to 5 kHz]	2 mA/A			
				(200 mA to 0.9A]				
254	A	P;T		[10 Hz to 300 Hz]	1600 μΑ/Α			

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Quantities - DC and L1	F	(400 H		7101 7401 7111 55	1	
		(400 II + 1177 3	כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
		(400 Hz to 1 kHz]	1700 μΑ/Α			
		(1 kHz to 5 kHz]	2000 μΑ/Α			
1		(0.9 A to 2 A]				
		[10 Hz to 300 Hz]	1000 μΑ/Α			
		(400 Hz to 1 kHz]	1000 μΑ/Α			
		(1 kHz to 5 kHz	1100 μΑ/Α			
		(2A to 11 A]				
		[36 Hz to 44 Hz]	$340~\mu\text{A/A}$			
		(44 Hz to 1.1 kHz]	$560~\mu\text{A/A}$			
		(1.1 kHz to 5.5 kHz]	800 μΑ/Α			
		(5.5 kHz to 11 kHz]	1400 μΑ/Α			
Current		(90 μA to 200 μA]		Portocal II	Datron 1281	
asuring Instruments	מכשירי מדידה	[10 Hz to 1 kHz]	$150~\mu\text{A/A} + 8~\text{nA}$	MetCal	Wavetek 9100	
		(1 kHz to 5 kHz]	$280~\mu\text{A/A} + 11~\text{nA}$	MTS	Wavetek 4808 Wavetek MTS 4950	
		(200 µA to 2 mA]		Automated	Fluke 5520A	
		[10 Hz to 1 kHz]	$120~\mu\text{A/A} + 78~\text{nA}$	Calibration Software  Manufacturer instructions	Fluke 5720A	
		(1 kHz to 5 kHz]	$200~\mu\text{A/A} + 78~\text{nA}$	Manufacturer instructions	Current Coils	
		(2 mA to 20 mA]				
		[10 Hz to 1 kHz]	$110~\mu\text{A/A} + 1~\mu\text{A}$			
		(1 kHz to 5 kHz]	$200~\mu\text{A/A} + 1~\mu\text{A}$			
				[10 Hz to 1 kHz] 110 $\mu$ A/A + 1 $\mu$ A	[10 Hz to 1 kHz] 110 μA/A + 1 μA	

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				(20 mA to 200 mA]			
270	Α	P;T		[10 Hz to 1 kHz]	$110 \mu A/A + 8 \mu A$		
271	Α	P		(1 kHz to 5 kHz]	$200~\mu\text{A/A} + 8~\mu\text{A}$		
				(200 mA to 2 A]			
272	A	P;T		[10 Hz to 1 kHz]	$260~\mu\text{A/A} + 78~\mu\text{A}$		
273	A	P		(1 kHz to 5 kHz]	$410 \ \mu A/A + 109 \ \mu A$		
				(2 A to 11 A]			
274	A	P;T		(10 Hz to 1 kHz]	$400 \mu A/A + 1 mA$		
275	Α	P;T		(1 kHz to 5 kHz]	$750 \ \mu A/A + 1.2 \ mA$		
276	A	P;T		(5 kHz to 10 kHz]	1.8  mA/A + 5  mA		
				(11 A to 20 A]			
277	Α	P;T		(10 Hz to 3 kHz	2.0  mA/A + 6.9  mA		
278	A	P;T		(3 kHz to 10 kHz]	5.0  mA/A + 23  mA		
				(20 A to 32 A]			
279	Α	P;T		(10 Hz to 100 Hz]	4.0  mA/A + 5.5  mA		
280	Α	P;T		(100 Hz to 440 Hz]	10 mA/A + 27 mA		
				(32 A to 160 A]			
281	Α	P;T		[10 Hz to 100 Hz]	4.0  mA/A + 28  mA		
				(160 A to 200 A]			
282	Α	P;T		(10 Hz to 100 Hz]	4.1 mA/A + 90 mA		
283	Α	P;T		(100 Hz to 440 Hz]	9 mA/A + 0.25 A		

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Electr	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - זו
					(200 A to 1000 A]			
284	A	P;T			[10 Hz to 40 Hz]	4.1  mA/A + 0.45  A		
285	A	P;T	DC Resistance, Resistors	התנגדות זרם ישר, נגדים	0.0001 Ω	$160~\text{m}\Omega/\Omega$		Standard resistance
286	A	P;T	Shunts	מיצד זרם	$0.0002~\Omega$	$35~\text{m}\Omega/\Omega$		Shunts IET Decade HARS-X
287	A	P;T			$0.0005~\Omega$	$35~\text{m}\Omega/\Omega$		Shallcross 833
288	A	P;T			$0.005~\Omega$	$4~\mathrm{m}\Omega/\Omega$		Wavetek 4953 Wavetek 4955
289	A	P;T			0.001 Ω	$16~\mathrm{m}\Omega/\Omega$		
290	A	P;T			0.01 Ω	$3~\mathrm{m}\Omega/\Omega$		
291	A	P;T			0.1 Ω	$0.3~\mathrm{m}\Omega/\Omega$		
292	A	P;T			1 Ω	$6~\mu\Omega/\Omega$		
293	A	P;T			10 Ω	$8~\mu\Omega/\Omega$		
294	A	P;T			50 Ω	$480~\mu\Omega/\Omega$		
295	A	P;T			100 Ω	11 μ $\Omega/\Omega$		
296	A	P;T			1 kΩ	$6~\mu\Omega/\Omega$		
297	A	P;T			10 kΩ	$10~\mu\Omega/\Omega$		
298	A	P;T			50 kΩ	$23~\mu\Omega/\Omega$		
299	A	P;T			100 kΩ	13 μ $\Omega$ / $\Omega$		
300	A	P;T			1 ΜΩ	24 μ $\Omega/\Omega$		
301	A	P;T			10 MΩ	$45$ μ $\Omega/\Omega$		
302	A	P;T			$100~\mathrm{M}\Omega$	$205~\mu\Omega/\Omega$		
303	A	P;T			1 GΩ	$5~\mathrm{m}\Omega/\Omega$		

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and	LF			ים ישר ותדר נמוך	ביול – גדלים חשמליים - זו
304	A	P;T	DC Resistance,	התנגדות זרם ישר,	(1 Ω to 10 Ω]	190 μΩ	Portocal II	Wavetek 9100
305	A	P;T	Sources	מחוללים	$10\Omega$	$16~\mu\Omega/\Omega$	MetCal	Fluke 5520A
306	A	P;T			$[10 \Omega \text{ to } 20 \Omega]$	82 μΩ/Ω	MTS	Fluke 5720 A
307	A	P;T			$(20 \Omega \text{ to } 100 \Omega]$	17 μΩ/Ω	Automated Calibration Software	Datron 1281 Wavetek 4808
308	A	P;T			$100\Omega$	27 μΩ/Ω	Manufacturer instructions	Standard resistance
309	A	P;T			$(100~\Omega~to~200~\Omega]$	$60~\mu\Omega/\Omega$		Wavetek MTS 4950
310	A	P;T			(200 $\Omega$ to 1 $k\Omega$ ]	$17~\mu\Omega/\Omega$		
311	A	P;T			$1~\mathrm{k}\Omega$	5.9 μΩ/Ω		
312	A	P;T			$(1 \text{ k}\Omega \text{ to } 2 \text{ k}\Omega]$	13 μΩ/Ω		
313	A	P;T			$(2 \text{ k}\Omega \text{ to } 10 \text{ k}\Omega]$	$175$ μ $\Omega/\Omega$		
314	A	P;T			$10\mathrm{k}\Omega$	5.8 μΩ/Ω		
315	A	P;T			$(10 \text{ k}\Omega \text{ to } 20 \text{ k}\Omega]$	13 μΩ/Ω		
316	A	P;T			$(20~k\Omega$ to $100~k\Omega]$	24 μΩ/Ω		
317	A	P;T			$100~\mathrm{k}\Omega$	11 μΩ/Ω		
318	A	P;T			$(100~\text{k}\Omega~\text{to}~200~\text{k}\Omega]$	$16$ μ $\Omega/\Omega$		
319	A	P;T			$(200~k\Omega$ to $1~M\Omega]$	45 μ $\Omega/\Omega$		
320	A	P;T			1 ΜΩ	20 μΩ/Ω		
321	A	P;T			$(1 \text{ M}\Omega \text{ to } 2 \text{ M}\Omega]$	170 μΩ/Ω		
322	A	P;T			$(2 \text{ M}\Omega \text{ to } 10 \text{ M}\Omega]$	82 μΩ/Ω		
323	A	P;T			$10~\mathrm{M}\Omega$	34 μΩ/Ω		

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electr	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
324	A	P;T			(10 M $\Omega$ to 20 M $\Omega$ ]	2 mΩ/Ω		
325	A	P;T			$(20~\text{M}\Omega~\text{to}~100~\text{M}\Omega]$	620 μΩ/Ω	Portocal II	Wavetek MTS 4950
326	Α	P;T			$100~\mathrm{M}\Omega$	$240~\mu\Omega/\Omega$	MetCal	Datron 1281
327	Α	P;T			$(100~\text{M}\Omega~\text{to}~200~\text{M}\Omega]$	$240 \ \mu\Omega/\Omega + 9 \ k\Omega$	MTS	Wavetek 9100
328	A	P;T			(200 M $\Omega$ to 2 G $\Omega$ ]	$4.5 \text{ m}\Omega/\Omega + 900 \Omega$	Automated Calibration Software	QCC 23-135
329	A	P;T					Manufacturer instructions	
330	A	P;T	DC Resistance, Measuring	התנגדות זרם ישר, מכשירי	$(1 \ \mu\Omega \ to \ 10 \ \Omega]$	21 μΩ/Ω	Portocal II	Wavetek MTS 4950
331	A	P;T	Instruments	מדידה	$(10 \Omega \text{ to } 100 \Omega]$	9 μΩ/Ω	MetCal	Datron 1281
332	Α	P;T			$(100 \Omega \text{ to } 10 \text{ k}\Omega]$	8 μΩ/Ω	MTS	Wavetek 9100
333	A	P;T			$(10~\text{k}\Omega~\text{to}~100~\text{k}\Omega]$	11 μΩ/Ω	Automated Calibration Software	QCC 23-135
334	A	P;T			$(100 \text{ k}\Omega \text{ to } 1 \text{ M}\Omega]$	24 μΩ/Ω	Manufacturer instructions	
335	A	P;T			$(1~\text{M}\Omega~\text{to}~10~\text{M}\Omega]$	$45$ μ $\Omega/\Omega$		
336	A	P;T			(10 M $\Omega$ to 100 M $\Omega$ ]	210 μΩ/Ω		
337	Α	P;T			$(100~\text{M}\Omega~\text{to}~1~\text{G}\Omega]$	8.4 mΩ/Ω		

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibre	ation –	Electr	ical Quantities - DC and	LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
338	A	P;T			(10 GΩ to 100 GΩ]	52 mΩ/Ω			
			Capacitance,	קיבול	(0.5 nF to 4 nF]		Portocal II	Wavetek 9100	
339	A	P;T	Measuring Instruments	מכשירי מדידה	Up to 350 Hz]	3  mF/F + 15  pF	MetCal	Standard Capacitors	
340	A	P;T			(350 Hz to 1.5 kHz]	6~mF/F + 30~pF	Automated	Fluke 5520 A	
					(4 nF to 40 nF]		Calibration Software  Manufacturer instructions	GR Capacitance Decade Standard Capacitors	
341	A	P;T			Up to 350 Hz]	3  mF/F + 30  pF	Manufacturer instructions	Standard Capacitors	
342	A	P;T			(350 Hz to 1.5 kHz]	6  mF/F + 60  pF			
					(40 nF to 400 nF]				
343	A	P;T			Up to 350 Hz]	3  mF/F + 160  pF			
344	A	P;T			(350 Hz to 1.5 kHz]	6  mF/F + 320  pF			
					(400 nF to 4 μF]				
345	A	P;T			Up to 350 Hz]	3  mF/F + 1.6  nF			
346	A	P;T			(350 Hz to 1.5 kHz]	8  mF/F + 3.2  nF			
					(4 μF to 40 μF]				

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## **Schedule of Accreditation**

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Calibra	ation –	Electr	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
347	A	P;T			Up to 350 Hz]	5 mF/F + 16 nF		
348	A	P;T			(350 Hz to 1.5 kHz]	10  mF/F + 32  nF		
					(40 μF to 400 μF]			
349	A	P;T			Up to 350 Hz]	5  mF/F + 160  nF		
350	A	P;T			(350 Hz to 1.5 kHz]	10  mF/F + 320  nF		
					(400 μF to 4 mF]			
351	A	P;T			Up to 350 Hz]	5  mF/F + 16  nF		
352	A	P;T			(350 Hz to 1.5 kHz]	10  mF/F + 3.2  nF		
					(4 mF to 40 mF]			
353	A	P;T			Up to 350 Hz]	$10 \text{ mF/F} + 60  \mu\text{F}$		
354	A	P;T			(350 Hz to 1.5 kHz]	$20~mF/F + 120~\mu F$		
			Capacitance,	l .	0.001 μF		Manufacturer instructions	
355	A	P	Capacitors	קבלים	1000 Hz	0.6 mF/F		
					0.005 μF			
356	A	P			1000 Hz	0.6 mF/F		
					0.01 μF			
357	A	P			1000 Hz	0.6 mF/F		
					0.05 μF			
358	A	P			1000 Hz	0.6 mF/F		
					0.1 μF			

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## **Schedule of Accreditation**

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Calibra	ation –	Electri	ical Quantities - DC and	LF			ם ישר ותדר נמוך	כיול – גדלים חשמליים - זר
359	A	P			1000 Hz	0.6 mF/F		
360		Р,Т	Phase angle, Measurement Phase angle meters		(0° to 90°) Frequency: [45 Hz to 65 Hz] Frequency: [65 Hz to 500 Hz] Parameters: V: 32 mV to 600 V I: 32 mA to 20 A Alternating V: 10 mV to 5 V	0.14° 0.21°	Manufacturer Instructions	Fluke 5520A Fluke 5522A  Electrical Test Equipment calibrator
361	A	P,T	AC Power, Measurement Power Meters		When current transducer not allowed  [1mW to 20 kW] Power factor: [0-1]	3.5 %	MetCal Automated Calibration Software	Fluke 5520A Fluke 5522A
362	A	P,T	Power factor, Measurement Power Meters		Frequency: [45 Hz to 65Hz] [ 0-1] Power: [1mW to 20 kW] Frequency: [45 Hz to 65Hz]	0.14	Manufacturer instruction	Electrical Test Equipment calibrator
363	A	P,T	DC Power, Measurement Power Meters		[10 mW to 20 kW]	0.5 %		
364 365 366	A	P,T P,T P,T	Continuity resistance Resistance, measuring instruments	התנגדות רציפות, מכשירי מדידת התנגדות	0.20 Ω to 20 Ω 100 Ω 1 kΩ	1.5% 1.2% 1.2%	MetCal Automated Calibration Softwar Manufacturer instructions	TRANSMILLE 3200 Electrical Test Equipment Calibrator
367		P,T	Continuity current Current measuring instruments	זרם רציפות מכשירי מדידת זרם	(0 mA to 320 mA]	4%		

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## **Schedule of Accreditation**

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Calibre	ation –	Electr	ical Quantities - DC and	LF			ם ישר ותדר נמוך	כיול – גדלים חשמליים - זו
368	A	P,T	Insulation resistance Resistance, measuring	התנגדות של בידוד מכשירי מדידת התנגדות	$0.00~\Omega$ to $5.00~\text{M}\Omega$	3.2%		
369	Α	P,T	instruments		$5$ M $\Omega$ to $2$ G $\Omega$	3.6%		
370	Α	P,T			$2~\mathrm{G}~\Omega$ to $10~\mathrm{G}\Omega$	5.8%		
371	A	P,T			$1~\mathrm{G}\Omega$ to $1~\mathrm{T}\Omega$	5.8%		
			Residual current				MetCal	
			AC Residual Current,	זרם חילופין שיורי			Automated Calibration	TRANSMILLE 3200 Electrical Test
372	A	P,T	Sensing Devices (RCD)	מכשירי חישה (RCD)	3.00 mA to 10.00 mA	0.250 mA/A	Software	Equipment Calibrator
373	A	P,T			10.1 mA to 100 mA	1.39 mA/A		Equipment cumorator
374	A	P,T			101 mA to 1 A	7.81 mA/A	Manufacturer instructions	
375	Α	P,T			1.01 A to 3 A	34.8 mA/A		
					(< 190 m Sec.]			
376	A	P,T			3 mA to 10mA	0.65 mA/A		
377		P,T			10.1 mA to 100 mA	3.12 mA/A		
378		P,T			101 mA to 1 A	31.22 mA/A		

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## **Schedule of Accreditation**

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Calibra	ation –	Electr	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
379	A	P,T			1.01 A to 3A	138.6 mA/A		
			Residual current duration AC Loop Resistance	התנגדות לולאה בזרם חילופין				
380		P,T	Loop Testing Devices.	מכשירי בדיקת לולאה	0.05 Ω	0.0049 Ω		
381		P,T			0.1 Ω	0.0053 Ω		
382		P,T			0.22 Ω	0.0059 Ω		
383		P,T			0.33 Ω	0.0065 Ω		
384		P,T			0.5 Ω	0.0076 Ω		
385		P,T			1 Ω	0.010 Ω		
386		P,T	-		5 Ω	0.033 Ω		
387		P,T			10 Ω	0.062 Ω		
388		P,T			100 Ω	0.582 Ω		
389	A	P,T			1 k Ω	5.77 Ω		

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## **Schedule of Accreditation**

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Calibro	ution –	Electri	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
390	A	P,T	Auto Loop Resistance AC Auto Loop Resistance. Loop Testing devices.	התנגדות לולאה בזרם AC מכשירי בדיקת לולאה.	$1\Omega$	0.021 Ω	MetCal Automated Calibration Software Manufacturer instructions	TRANSMILLE 3200 Electrical Test Equipment Calibrator
391	A	P,T	Earth Bond Resistance	התנגדות בדיקת חיבור להארקה	0.05 Ω	0.0049 Ω		
392	A	P,T	Bond Resistance	PAT'מכשירי	0.1 Ω	0.0053 Ω		
393	A	P,T	PAT (Portable Appliance Tester)		0.22 Ω	$0.0059~\Omega$		
394	A	P,T	Tester)		0.33 Ω	0.0065 Ω		
395	A	P,T			0.5 Ω	$0.0076~\Omega$		
396	11	P,T			1 Ω	0.010 Ω		
397	**	P,T			5 Ω	0.033 Ω		
398	A	P,T			10 Ω	0.062 Ω		
399	A	P,T			$100 \Omega$	0.582 Ω		
400	A	P,T			1 k Ω	5.77 Ω		

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## **Schedule of Accreditation**

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Calibro	ation –	Electri	ical Quantities - DC and	LF	יול – גדלים חשמליים - זרם ישר ותדר נמוך			
401	A	P,T	Earth Bond Current Bond current,	זרם בדיקת חיבור להארקה	100.0 mA	9.3 mA		
402	A	P,T	PAT (Portable Appliance	PAT־מכשירי	10.00 A	0.24 A		
403	A	P,T	Tester)		30.00 A	0.59 A		
404	A	P,T	Insulation Resistance Resistance,	התנגדות בידוד,	$0~\Omega$ to $5~M\Omega$	3 %		
405	A	P,T	PAT (Portable Appliance Tester)	PAT מכשירי	$5 M\Omega$ to $2~G\Omega$	3.5 %		
406	A	P,T	Leakage Current,	זליגת זרם להארקה	2.000 mA	0.038 mA	MetCal	TRANSMILLE 3200 Electrical Test
407	A	P,T	PAT (Portable Appliance Tester)	PATימכשירי	4.700 mA	0.084 mA		Equipment
408	A	P,T			7.700 mA	0.136 mA	Manufacturer instructions	Calibrator
409	A	P,T	Flash Voltage PAT (Portable Appliance Tester)	מתח פריצת בידוד מכשיריPAT	Class 1 (1.5 kV) (1 kV to 1.8 kV] 1000 V	57 V		
410		P,T	10501)		1500 V	81 V		
411	A	P,T			Class 2 (3 kV) (2 kV to 3 kV] 3000 V	151 V		
412	A	P,T	Flash Current PAT (Portable Appliance Tester)	זרם פריצת בידוד מכשירי PAT	(1 mA to 3 mA] 1.00 mA	0.06 mA		

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The certificate attached is an integral part of the schedule and is numbered identically המעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח או מחלק בלתי נפרד ממנו ומספרה זהה למספר הנספח ומספרה זה למספר הנספר או מחלק בלתי נפרד ממנו ומספרה זהה למספר הנספר או מחלק בלתי נפרד ממנו ומספרה זהה למספר הנספר או מחלק בלתי נפרד ממנו ומספרה זהה למספר הנספר או מחלק בלתי נפרד ממנו ומספרה זהה למספר הנספר או מחלק בלתי נפרד ממנו ומספרה זהה למספר הנספר או מחלק בלתי נפרד ממנו ומספרה זה המספר הנספר או מחלק בלתי נפרד ממנו ומספרה זה המספר הנספר או מחלק בלתי נפרד ממנו ומספרה זה המספר הנספר או מחלק בלתי נפרד ממנו ומספר הוות המספר המספר הנספר או מחלק בלתי נפרד ממנו ומספר הוות המספר הוות ה

## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibre	ation –	Electr	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - זי
413	A	P,T	Line Voltage Measurement of line voltage	מתח רשת חשמל, מדידת מתח רשת חשמל	200 V (rms) ) to 260 V(rms)	2.9 V(rms)		
414 415 416 417 418	A A A	P,T P,T P,T P,T	Breakdown/Hipot Measurement of high voltage	מדידת מתח גבוה	(3 kV AC @ 50 Hz) 1.00 kV 2.00 kV 3.00 kV (12 kV AC @ 50 Hz)	0.05 kV 0.06 kV 0.06 kV	MetCal Automated Calibration Software Manufacturer instructions	TRANSMILLE 3200 Electrical Test Equipment  Calibrator

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibro	ation –	Electri	ical Quantities - DC and LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
419	A	P,T			0.07 kV			
420	A	P,T		4.00 kV	0.08 kV			
421	A	P,T		6.00 kV	0.10 kV			
				8.00 kV	0.11 kV			
422	A	P,T		10.00 kV				
423	A	P,T		(25 kV AC @ 50 Hz) 12 kV to 25 kV	1.2% O.R.		HV Probe 80K-40 DMM	
				3 kV DC			TRANSMILLE 3200	
424	A	P,T		1.00 kV	0.05 kV			
425	A	P,T		2.00 kV	0.06 kV			
426	A	P,T		3.00 kV	0.06 kV			
				(12 kV DC)	0.07.17			
427		P,T		4.00 kV	0.07 kV			
428		P,T P.T		6.00 kV	0.08 kV			
429 430		P,T P,T		8.00 kV 10.00 kV	0.09 kV 0.10 kV			
430		P,T		12.00 kV	0.10 kV 0.12 kV			
431	<i>r</i> <b>1</b>	1,1		12.00 R V	U.12 K V			

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electr	ical Quantities - DC and	LF		ם ישר ותדר נמוך	כיול – גדלים חשמליים - זו	
					(40 kV DC)			HV Probe 80K-40 DMM
432	Α	P,T			12 kV to 40 kV	1.0% O.R.		TRANSMILLE 3200
			Measurement of current at high voltage	מדידת זרם במתח גבוה	1 kV AC @ 50 Hz			
433	Α	P,T			200 µA	1.7 μΑ		
434	A	P,T			2.00 mA	0.04 mA		
435	Α	P,T			20.00 mA	0.16 mA		
436	A	P,T			1 kV DC			
437	A	P,T			200 μA	1.7 μΑ		
438	A	P,T			2.00 mA	0.04 mA		
439	Α	P,T			20.00 mA	0.16 mA		
			DC High Voltage, Source	מחוללי מתח גבוה ישר	40 kV DC)			SPELLMAN SL40P2000 HV Probe 80K-40
440	A	P,T			1 kV to 40 kV	2.4% O.R.		DMM

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Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	alibration – Electrical Quantities - RF Frequency, Time						דר גבוה, זמן	כיול – גדלים חשמליים - ת
441	A	P	Frequency, Sources	תדר, מחוללי תדר	[0.037 Hz to 10 MHz]	10 <sup>-11</sup> (24 h)	Portocal II MetCal 6.11	FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R
442	A	P			[10 MHz to 3.2 GHz]	5×10 <sup>-9</sup> (0.3 h)	Portocal II MetCal 6.11	FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R (with 9500 + 9530)
443	A	Т			[10 MHz to 3.2 GHz]	4.8×10 <sup>-5</sup> (0.3 h)	Portocal II MetCal 6.11	Wavetek 9500 H.P.5248 M H.P. 53132 A With Internal Reference
444	A	P	Frequency.	תדר,	[0.1 Hz to 100 MHz]	4.8×10 <sup>-9</sup> (0.3 h)		With Ref. Locked to 910R
445	A	P	Counters	מוני תדר	[100 MHz to 3 GHz]	4.8×10 <sup>-10</sup> (0.3 h)		With Ref. Locked to 910R (with 9500 + 9530)
446	A	T			[0.1 Hz to 3 GHz]	1.4×10 <sup>-5</sup> (0.3 h)		With Internal Reference
447	A	P;T	Timers, stopwatches	שעוני עצר, מוני זמן	[1 sec to 24 hr]	0.1 sec	Manufacturer instructions הוראות יצרן	השוואה למדיד אב

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Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Electr	ical Quantities - RF Freq	uency, Time			ר גבוה, זמן	כיול – גדלים חשמליים - תד
448	A	P;T	Oscilloscope Time markers function: Square wave, Pulse, Narrow Triangle	ציר אופקי במשקף תנודות	[9 ns to 55 sec]	5×10 <sup>-9</sup>	Portocal II Software MetCal Software	Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz
449 450		P;T	Oscilloscope Amplitude Square Wave	ציר אנכי במשקף תנודות	Input impedance 1 MΩ  Peak to peak amplitude  (40 μV to 1 mV ]  (1 mV to 200 V]	$10 \text{ mV/V} + 10 \mu\text{V}$ $1 \text{ mV/V} + 10 \mu\text{V}$	Portocal II Software MetCal Software	Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz
451		P;T	Oscilloscope Amplitude Square Wave	ציר אנכי במשקף תנודות	Peak to peak amplitude (40 µV to 1 mV pk-pk]	10 mV/V + 10 μV	Portocal II Software MetCal Software	Wavetek 9500
453		P;T	Oscilloscope Rise Time	זמן עלית האות של משקף תנודות	(1 mV to 5 V pk-pk] Rise time, From 150 ps]	$1 \text{ mV/V} + 10 \mu\text{V}$ $14 \text{ ps}$	Portocal II Software MetCal Software	Wavetek 9500
454 455		P;T P;T	Oscilloscope Bandwidth:	רוחב סרט של משקף תנודות	[0.1 Hz to 300 MHz] [300 MHz to 550 MHz]	0.23 db 0.23 db	Portocal II Software MetCal Software	Wavetek 9500 Tektronix 284 Pule generator rise time
456 457		P;T P;T			[550 MHz to 1.1GHz] [1.1 GHz to 3.2 GHz ]	0.29 db 0.36 db		70 ps

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibro	Calibration – Electrical Quantities - RF Frequency, Time					כיול – גדלים חשמליים - תדר גבוה, זמן			
458	A	P;T	Oscilloscope	מישוריות האות כתלות בתדר ביחס לתדר הייחוס	[0.1 Hz to 300 MHz]	2.3 %	Portocal II Software	Wavetek 9500	
459	A	P;T	Flatness	atness	[300 MHz to 550 MHz]	3.8 %	MetCal Software	Leveled Sine Wave Amplitude	
460	A	P;T			[550 MHz to 1.1 GHz]	4.9 %		50 kHz Ref	
461	A	P;T			[1.1 GHz to 3.2 GHz]	6.0 %			
462	A	P;T	Oscilloscope Input Capacitance	קיבול כניסה של משקף תנודות	[1 pF to 65 pF]	7 mF/F	Portocal II Software MetCal Software	Wavetek 9500 Input impedance 50 Ω	

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# **Schedule of Accreditation**

Item	Scope Type	Site	3		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Mecha	nical Quantities - Form	, Angle			ו, זווית	כיול – גדלים מכניים - צורר
463	A	P	Flank Angle Screw Plug Gauges (parallel) including check and setting Plug	זווית השן מדיד הברגה זכר מקביל	Plug Diameter [1 mm to 305 mm]	[2+(800/M×P)] Minutes of arc		<b>M</b> is projector magnification and <i>P</i> is pitch in mm
464	. A	P	Flank angle Screw Plug Gauges (taper)	זווית השן מדיד הברגה זכר קוני	Plug Diameter [1 mm to 305 mm]	[2+(800/M×P)] Minutes of arc		<i>M</i> is projector magnification and <i>P</i> is pitch in mm
465	Α	P	Flatness of Optical Flats in diameter of 10 mm – 50 mm	מישוריות של משטחים אופטיים בעלי קוטר 50 mm בעלי	Above 0.05 μm	0.1 μm	FED-GG-0-635 JIS B 7430 JIS B 7431	Optical flat/parallel מערכת כיול מקבילונים ועדשה מישורית The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by
466	A	P	Parallelism of Optical Parallels in diameter of 10 mm – 50 mm	מקבילות של משטחים אופטיים בעלי קוטר 10 – 50 mm	Above 0.01 μm	0.1 µm		The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by

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Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Mecha	nical Quantities - Form	, Angle			ה, זווית	כיול – גדלים מכניים - צורו
467	A	P;T	Flatness of Granites or Cast iron surfaces in Grade 00	מישורית של לוחות משטח גרניט וברזל יציקה ברמה 00	Above 0.1 μm	[1.5+0.8* length] μm	DIN 876 P1,2 ISO 8152 P1,2 GGG-P-463-C	עד 2 0.09 m² נבדק באמצעות אורך. מעל 2 0.09 m² נבדק במערכת פלסים אלקטרוניים. The uncertainty quoted is for the departure from flatness, straightness, parallelism, or squareness i.e. the distance separating the two parallel planes which, just enclose the surface under consideration
								(Length in m)
468	A	Р	Straightness, flatness and parallelism of Granite, Cast iron and Steel straightedges in Grade 00	ישרות, מישוריות, מקבילות של סרגל ישרות מתכת או גרניט ברמה 00	Above 1 μm	4.3 μm	DIN 874 P.1	גששי אורך
469	A	P	Straightness Knife edge, straight edge	סרגל שערה	Up to 500 mm]	1.5 μm	DIN 874 P.2	מקור אור מונוכרומטי, גששי אורך
470	A	P	Flatness, Parallels	מקבילים	Up to 50*100*400]	2 μm	DIN 6346 DIN 7151 DIN 7168	גששי אורך
471	A	P	Parallelism, Parallels	מקבילים	Up to 50*100*400]	2 μm	DIN 6346 DIN 7151 DIN 7168	גששי אורך

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Calibro	ation –	Mecha	unical Quantities - Form, Angle			רה, זווית	כיול – גדלים מכניים - צוי
472	A	P	Perpendicularity, ,חת,	ניצו Up to 300 mm]	3.0 μm	DIN-875	גששי אורך
473	A	P	Square, blade type	(300 mm to 600 mm]	5 μm	JIS B 7526	מד ניצבות
474	. A	P		(600 mm to 900 mm]	8 μm		
475	A	P	Parallelism vdin	מקו Up to 300 mm]	3 μm	DIN-875	גששי אורך
476	A	P	Square, blade type	(300 mm to 600 mm]	5 μm	JIS B 7526	
477	A	P		(600 mm to 900 mm]	8 μm		
478	A	P	Flatness, יריות	מיש Up to 300 mm]	3 µm		
479	A	P	Square, blade type	(300 mm to 600 mm]	5 μm		
480	A	P		(600 mm to 900 mm]	8 μm		
481	A	P	Perpendicularity, Cylinder ניצבות	גלייס Up to 600 mm]	2 μm	JIS B 7539	
482	A	P	Perpendicularity,	ניצו Up to 100 mm]	3 μm	DIN 875	
483	A	P	Universal Box Angles	אביכ (100 mm to 300 mm]	5 μm	DIN 876	
484	. A	P		(300 mm to 600 mm]	8 μm		
485	A	P	Flatness,	מיש Up to 100 mm]	3 μm	DIN 875	
486	A	P	Universal Box Angles	אביס (100 mm to 300 mm]	5 μm	DIN 876	
487	A	P		(300 mm to 600 mm]	8 μm		

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Mecha	unical Quantities - Form, Angle			ו, זווית	כיול – גדלים מכניים - צורר
488	A	P	Parallelism Universal Roy Angles	- F 10 100 11111	3 μm	DIN 875 DIN 876	
489	A	P	Universal Box Angles גביזר דפינה אוניברסאלי	(100 mm to 300 mm]	5 μm	DIN 870	
490	A	P		(300 mm to 600 mm]	8 μm		
491	A	P	Squareness ברך, קוביה	Up to 600 mm]	[3 + 1 per 100 mm] µm	WI-C050	מד ניצבות
			Right angle and box angle plate				
492	A	P	Parallelism ברך, קוביה	Up to 600 mm]	[1 + (1 per 100 mm)] μm	WI-C050	מד ניצבות
			Right angle and box angle plate				
493	A	P	Perpendicularity חוד ניצבות	600 mm	2.1 μm	נתוני יצרן	השוואה למדיד אב לניצבות
			Square master				
494	A	P	Perpendicularity	Up to 150 mm]	2.1 μm	BS 3731	Grade 00
			Vee blocks			JIS B 7540	גששי אורך גליליים
495	A	P	Flatness, ריזמות	Up to 150 mm]	2.1 μm	BS 3731	Grade 00
			Vee blocks			JIS B 7540	גששי אורך גליליים
496	A	P	Parallelism	Up to 150 mm]	2.1 μm	BS 3731	Grade 00
			ריזמות Vee blocks			JIS B 7540	גששי אורך גליליים
497	A	P	Angle ווית	Up to 500 mm]	[1 + (10* length in m)] µm	BS 3064	Angle is estimated by
			Sines bars and tables סינוס	,		GGG-B 121b	measuring distance
						DIN 2273	מקבילונים בלוק זוויתי
498	A	P	Angle אוטוקולימטור	10′	1"	הוראות יצרן	מייצר זוויות קטנות
			Autocollimator				

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibr	libration – Mechanical Quantities - Form, Angle					כיול – גדלים מכניים - צורה, זווית			
499	A	P	Angle Level	פלס	± 5°	0.5′′	DIN 887 BS 958	1 μ/m sensitivity מייצר זוויות קטנות	
500	) A	P	Angle Clinometer	קלינומטר	Up to 90°]	10″	DIN 887 BS 958	מייצר זוויות קטנות	
501	A	P	Angle Bevel protractor	מד זווית מתכוונן	up to 360 °)	3′	BS 1685	בלוק זוויתי גששי אורך מד ניצבות	
502	A	P;T	Rotational Speed Mechanical tachometer	מהירות סיבוב (סלייד) מד סלייד מכני	[1 to 5000] RPM	0.1 % OR or 0.2 RPM Whichever is greater	Manufacturer instructions המלצות יצרן	Counter מונה	
503	A	P;T	Rotational Speed Optical tachometer	מהירות סיבוב (סלייד) מד סלייד אופטי	[1 to 2500] RPM	0.02 % OR or 1 resolution Whichever is greater		Function generator מחולל אותות	
504	A	P;T	Rotational Speed Optical tachometer	מהירות סיבוב (סלייד) מד סלייד אופטי	[2500 to 99999] RPM	0.005 % OR		Function generator מחולל אותות	

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Item	Scop e Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	tion – l	Mechan	ical Quantities - Hardn	ess Meters			קושיות	כיול – גדלים מכניים - מדי
505 506		P;T	Rockwell hardness testing machine	מכשירים למדידת קשיות בשיטת רוקוול	HRA [20 to 95] HRBW	0.45 HRA	ASTM E18 ISO 6508-2	Indirect verification יסטנדרטי השוואה לחומר יחוס סטנדרטי
507	A	P;T			[10 to 100] HRC [10 to 70]	0.7 HRBW 0.45 HRC		
508		P;T			HREW [70 to 100]	0.9 HREW		
509		P;T P;T			HR15N [70 to 94] HR30N	0.5 HR15N 0.5 HR30N		
511	A	P;T			[42 to 86] HR45N [20 to 77]	0.5 HR45N		
512	A	P;T			HR15TW [67 to 93]	0.7 HR15TW		
513		P;T			HR30TW [29 to 82] HR45TW	0.7 HR30TW		
514	A	P;T			[10 to 72]	1.1 HR45TW		
515	A	P;T	Brinell hardness testing machine	מכשירים למדידת קשיות בשיטת ברינל	HBW 2.5 / 187.5	2% HBW	ASTM E10	Indirect verification השוואה לחומר יחוס סטנדרטי
516	A	P;T	Vickers hardness testing	מכשירים למדידת קשיות בשיטת וויקרס	(0.1 to 0.5) HV	1.5% HV	ASTM E384	Indirect verification
517	A	P;T	machine	machine archine	(1 to 100) HV	1.2% HV	ISO 6507-2	השוואה לחומר יחוס סטנדרטי

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Item	Scope Type	Site	Measurand In.	strument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	tion – M	<b>l</b> echant	ical Quantities - Hardn	ess Meters			קושיות	כיול – גדלים מכניים - מדי
			Shore hardness testing equipment (durometer)	מכשירים למדידת קשיות בשיטת שור	Type A Instruments		ASTM D2240 ISO 21509 ISO 18898	Direct verification  Shore כיול כח קפיץ ביחידות  Durocalibrator
518	A	P	SHORE A	A שור	[0 to 100] Shore	0.4 SHORE A	130 10090	Durocanorator
519	A	P	Indenter extension	אורך החודרן	[0.1 to 2.54] mm	0.010 mm		בדיקת פרמטרים של החודרן
520	A	P	Indenter diameter	קוטר חוד החודרן	[0.76 to 0.82] mm	0.008 mm		Profile projector
521	A	P	Indenter angle	זווית החודרן	[34.75° to 35.25°]	0.05°		Microscope
522	A	P	Intender diameter	קוטר החודרן	[1.1 to 1.4] mm	0.03 mm		Indenters with parameters out of the nominal range
523	A	P	Presser foot hole diameter	קוטר קדח הבסיס	[2.5 to 3.5] mm	0.03 mm		may be calibrated at stated uncertainties as well
524	A	P	Presser foot diameter	קוטר בסיס לחיצה	[10 to 50] mm	0.05 mm		
					Type D Instruments			
525	A	P	SHORE D	D שור	[10 to 100] Shore	0.4 SHORE D		
526	A	P	Indenter extension	אורך החודרן	[0.1 to 2.54] mm	0.010 mm		
527	A	P	Indenter radius	רדיוס חוד החודרן	[0.088 to 0.112] mm	0.008 mm		
528	A	P	Indenter angle	זווית החודרן	[29° to 31°]	0.05°		
529	A	P	Intender diameter	קוטר החודרן	[1.1 to 1.4] mm	0.03 mm		
530	A	P	Presser foot hole diameter	קוטר קדח הבסיס	[2.5 to 3.5] mm	0.03 mm		
531	A	P	Presser foot diameter	קוטר בסיס לחיצה	[10 to 50] mm	0.05 mm		

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## **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)		as an Expanded nty (95%)	Reference Documents	Remarks
Calibra	ation –	Mecha	ınical Quantities - Lengt	h					כיול – גדלים מכניים - אורך
532	A	P	Gauge Blocks Comparator	מערכת כיול מקבילונים	Up to 100 mm	0.05	5μm	Euramet cg-2	Gauge blocks
533	A	P	Length,	אורד,		Class	(see note)	DIN 861	קומפרטור מקבילונים
			Gauge Blocks (by Comparison)	מקבילונים		C	D	ISO 3650	Class C uncertainties apply
534	A	P	Comparison)		Up to 10 mm}	0.08 µm	0.10 µm	BS 4311 NF E11-010	to the measurement of length of steel gauges by comparison with grade K
535	A	P			(10 mm to 25 mm]	0.10 μm	0.13 µm	OIML No. 30	standards of length of a similar material. Class C
536	A	P			Sizes: 30, 40, 50	0.12 μm	0.17 μm	BS 888	uncertainties apply to new grade 0, 1 and 2 gauges to
537	A	P			Sizes: 60, 70, 75	0.15 μm	0.21 μm		the aforementioned standard
538	A	P			Sizes: 80, 90, 100	0.18 μm	0.25 μm		and represent the best capability for all grades of
539	A	P			Up to 0.4 in}	3 µin	4 μin		used gauges to the aforementioned standard.
540	A	P			(0.4 to 1 in]	4 μin	5 μin		Class D Class D uncertainties represent the
541	A	P			2 in	5 μin	7 μin		best capability for the measurement of length of
542	A	P			3 in	6 µin	8 µin		tungsten carbide and ceramic gauges by comparison with
543	A	P			4 in	7 μin	10 μin		grade K standards of length of a dissimilar material
544	A	P	Length	אורך,	160 mm	2	μm	DIN 861 P-2	מכונת מדידה
			Gauge Block accessories	אביזרים מקבילונים					SIP / TRIMOS 305M

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Calibra	ation –	Mecha	ınical Quantities - Lengt	h				כיול – גדלים מכניים - אורן
545	A	P	Length, Length Bars	אורך, מוטות אורך מדיד	Up to 775 mm]	[0.1 + 2×length] µm	BS 5317 ISO 3650 DIN 861	Length bar Length in m
546	Α	P	Length, Length Gauges	אורך, מדידי אורך	Up to 1000 mm]	[0.1 + 2.5×length] μm	ISO 3650 DIN 861 ASME B89.1.13	Length bar Length in m
547	A	P	Length, Step Gauge	אורך, מקבילונים מדורגים	Up to 600 mm]	[0.1 + 2.5×length in m] μm	נתוני יצרן	Length bar Length in m
548	Α	P	Length Measuring Machine	מכונת מדידת אורך	Up to 500 mm	$[0.1 + 2.5 \times length] \mu m$	Manufacturer instructions	Length bar Length in m
549 550		P P	Length, Plain Plug Gauges	אורך, מדידי תקע חלק	[1 to 25.4] mm (25 mm to 100] mm	1 μm 1.5 μm	ISO R/286 DIN 7162 DIN 7163 DIN 7164 H28/SEC.6 DIN 2269	מכונת מדידה SIP / TRIMOS 305M מיקרומטר שולחני
551 552	A	P P	Diameter Plain Rings	טבעות חלקות	[2 mm to 100 mm] (100 mm to 150 mm]	0.4 μm 1.5 μm	DIN 2250	מכונת מדידה SIP / TRIMOS 305M by comparison to gauge block in clamp
553	Α	P			(150 mm to 205 mm]	2 μm		calibration by comparison to standard plain ring provides lower uncertainties

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Mecha	nical Quantities - Lengt	h				כיול – גדלים מכניים - אורך
554	A	P	Diameter Thread Measuring Cylinders	תיילים לבדיקת מדיד הברגה	[0.1 mm to 6 mm]	0.5 μm	H28/SEC.22A	מכונת מדידה SIP / TRIMOS 305M
555		P	Pitch Diameter Screw Plug Gauges (parallel) including check and setting Plug	מדיד חברגה זכר – מקביל	Plug Diameter [1 mm to 100 mm] (100 mm to 305 mm]	3 μm 5 μm	F-STD-H-28 ISO 228/1-2 ISO 1502 ISO 2903/4 ISO 7/1,29 BS 919/1,2,3 BS 849 BS 3409/1,2 BS 4377/2 BS 21 DIN 103/9 DIN 405 DIN 2999/4 B.N.A.e HELI-COIL	כיול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיול – גדלים מכניים – צורה, זווית
557	A	P	Pitch Screw Plug Gauges (parallel) including check and setting Plug	פסיעת התבריג מדיד הברגה זכר מקביל	Plug Diameter [1 mm to 305 mm]	1.5 µm		

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Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Mecha	anical Quantities - Length	i			;	כיול – גדלים מכניים - אורז
558 559		P P	Pitch Diameter Screw Plug Gauges (taper)	מדיד הברגה זכר - קוני	Plug Diameter [1 mm to 100 mm] (100 mm to 305 mm]	3 μm 5 μm		כיול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיול – גדלים מכניים – צורה, זווית
560	A	P	Pitch Screw Plug Gauges (taper)	פסיעת התבריג מדיד הברגה זכר קוני	Plug Diameter [1 mm to 305 mm]	1.5 μm		
561	A	P	Pitch Diameter Thread rings (parallel)	טבעות הברגה – מקבילה	Ring diameter [1.2 mm to 3 mm]	Not relevant	F-STD-H 28 ISO 228/1-2	Go no go test by means of check plug
562	A	P			(3 mm to 100 mm]	4 μm	ISO 1502 ISO 2903/2904	מכונת מדידה SIP / TRIMOS 305M
563	A	P			(100 mm to 305 mm]	5 μm	BS 919/1,23 BS 84 DIN 103/9 DIN 405 DIN 2999/2 B.N.A.e	
564 565		P T	Micrometer External	מיקרומטר חיצוני	Up to 2000 mm]  Up to 600 mm]	Heads 2.0 μm Setting and extension rods: [1 + 5×length in m] μm Heads 3.0 μm Setting and extension rods:	ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502	מקבילונים מוטות אורך
566	A	P	Micrometer Internal	מיקרומטר פנים	Up to 300 mm] extension rod to 1000 mm]	[1 + 5×length in m] μm  Heads 2.0 μm  Setting and extension rods [1 + 5×length in m] μm	DIN 863 ASME B89.1.13	טבעות חלקות מכונת מדידה

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח מה למחשב המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשבח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשבח המצור מהווה החלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשבח המצור מהווה החלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשבח המצור מהווה החלק בלתי נפרד ממנו ומספרה הנספח המשבח המשבח המצור מהווה החלק בלתי נפרד ממנו ומספרה זה המצור מהווה המצור מתוח המצור מהווה החלק בלתי נפרד ממנו ומספרה המשבח המצור מתוח המצ

### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Mecha	nical Quantities - Lengt	h			•	כיול – גדלים מכניים - אורך
567	A	P;T	Micrometer Depth	מיקרומטר עומק	Up to 250 mm]	Heads 2.0 µm  Setting and extension rods [1 + 5×length in m] µm	DIN 863 ASME B89.1.13	מקבילונים
568 569		P T	Micrometers (indicating digital and electronic)	מיקרומטר (כולל דיגיטלי)	Up to 2000 mm]  Up to 600 mm]	[1 + 5×length in m] μm Minimum 1.5 μm [1 + 5×length in m] μm Minimum 3.0 μm	ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502	מקבילונים מוטות אורך
570 571		P P	Three point Internal and bore micrometer	מיקרומטר פנים תלת נקודתי	[2 mm to 50 mm] (50 mm to 150 mm]	2 μm 5 μm	DIN 863 Manufacturer instructions	טבעות חלקות
572	A	P	Micrometer head	ראש מיקרומטר	Up to 50 mm]	2 μm		
573	A	P	Height setting micrometer	מד גובה מיקרומטרי	Up to 300 mm]	Heads 1.0 μm between any two points. Stepped column 2.5 μm Overall performance 3.0 μm	ISO 7863	מקבילונים, מוטות אורך
574 575		P P	Riser Block	בסיס הגבהה למד גובה מיקרומטרי	Up to 150 mm] (150 to 300 mm]	2.5 μm 5 μm		
576	A	P;T	Vernier Caliper, depth Gauges	זחון ורנייר	Up to 2000 mm]	Overall performance [10 + 30× length in m] $\mu$ m	DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988	מקבילונים, מוטות אורך, בודק זחונים

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instru	ument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Mecha	nical Quantities - Length					כיול – גדלים מכניים - אורך
577	A	P;T	Caliper (digital and electronic)	זחון אלקטרוני ודיגיטלי	Up to 2000 mm]	Overall performance [10 + 30× length in m] μm	DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988	מקבילונים, מוטות אורך, בודק זחונים
578	A	P	Micrometer Heads Dial testers	מערכת כיול חוגנים	Up to 25 mm	0.2 μm		Gauge blocks
579	A	P;T	Height Gauge Electronic microprocessor Controlled height Gauge	מד גובה	Up to 1000 mm]	[1 + 5× length in m] μm	BS 1643 JIS B 7517	
580	A	P;T	Dial Indicator Length gauge	חוגן גשש אורך	Up to 3 mm]	0.3 μm	DIN 878 DIN 879	בודק חוגנים מכונת מדידה
581 582		P;T P:T	Zengur gauge		[3-60] mm	1 μm 1.5 μm	JIS B 7509 ANSI B89.1.10M	
583	A	P;T	Lever type dial indicator Lever type gauge	חוגן מנופי גשש מנופי	Up to 3 mm]	0.3 μm	NF E 11-056 BS 2795 PT.1 DIN 2270 MIL-I-18422D JIS B 7533	בודק חוגנים
584	. A	P;T	Thickness gauge	מד עובי	Up to 50 mm	2 μm	Manufacturer instructions	מקבילוני אורך Gauge blocks
585	A	P;T	Dial caliper gage (external type)	מד עובי זרועות	Up to 150 mm	10 μm	Manufacturer instructions	מקבילוני אורך Gauge blocks
586	A	P;T	Dial caliper gage (internal type)	מד חריצים	Up to 125 mm	10 μm	Manufacturer instructions	מיקרומטר, מקבילוני אורך Micrometer, Gauge blocks

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Mecha	ınical Quantities - Lengtl	h				כיול – גדלים מכניים - אורך
587	A	P	Feeler Gauge	מד מרווח עלים	Up to 1 mm]	4 μm	DIN 2275	מיקרומטר
588	A	P;T	Measuring microscope	מיקרוסקופ מדידה	Up to 300 mm	[2 + (25/M)] µm	נתוני יצרן	סרגל אופטי M is total magnification
589	A	P;T	Profile projectors	מטול פרופילים	Up to 300 mm	[2 + (25/M)] µm		סרגל אופטי M is total magnification
590	A	P	Bore comparators (bore gauge)	מד קדח גשר	[6 mm to 150 mm]	2 μm	JIS B 7515 MIL-G-26762A MIL-G-26762A	בודק חוגנים טבעות חלקות מיקרומטר
591	A	P	Bore comparators Cylinder gauge	פין מפציל	[1 mm to 18 mm]	2 μm		
592 593		P	Optical scale	סרגל אופטי	Up to 1 mm 1 mm – 300 mm	0.5 μm 1 μm	JIS B 7541 Manufacturer instructions	מכונת מדידה TRIMOS/ SIP 305M
594 595		P P	Measuring rule	סרגל מדידה	Up to 500] mm (500 to 2000] mm	20 μm 50 μm	DIN 866, JIS-B 7516 Manufacturer instructions	מיקרוסקופ מדידה מיקרוסקופ מדידה כייל סרגלי וסרטי מדידה Measuring microscope Scale and Tape Calibration Unit.
596 597	A	Р	Measuring tape	סרט מדידה	Up to 10] m (10 to 50] m	0.10 mm 0.40 mm	OIML-R-35	כייל סרגלי וסרטי מדידה Scale and Tape Calibration Unit.
598	A	P;T	Length Length meter	אורך מד אורך	[1 to 1000] m	0.01 m or 0.2 % OR Whichever is greater		Mechanical tachometer (Mode "m") מונה מטרים

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Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Mecha	ınical Quantities - Lengti	'n				כיול – גדלים מכניים - אורך
599	A	P;T	Surface Speed Surface Speed meter	מהירות פני השטח מד מהירות פני השטח	[2 to 500] m/min	0.1 m/min or 0.2 % or Whichever is greater		Mechanical tachometer (Mode "m/min") מד מהירות
600 601 602 603 604 605	A A A A	P P P P	Test sieves	נפות	Nominal aperture size :  Up to 0.2 mm 0.2 mm – 1 mm 1 mm – 5 mm 5 mm – 15 mm 15 mm – 30 mm Above 30 mm	0.003 mm 0.005 mm 0.010 mm 0.020 mm 0.050 mm 0.10 mm	ASTM E11 ISO 3310 BS 410	מטול פרופילים, זחון Profile projector, caliper.
606	A	P:T	Extensometer	מד התארכות	[0.01 mm to 50 mm]	0.004 mm	ASTM E83 ISO 9513 ISO 5893	Extensometer calibrator
607	Α	P:T	Extensometer (displacement)	מד התארכות	[0.01 mm to 1000 mm]	0.006 mm	Manufacturer instructions	High precision dial gauge, Length gauge
608 609 610	A A	P;T P;T P;T	Length measurements	מדידת אורך	Up to 125 mm] (125 mm to 200 mm] (200 mm to 600 mm] (600 mm to 2000 mm]	0.003 mm 0.005 mm 0.007 mm 0.010 mm	Customer requirements	

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### **Schedule of Accreditation**

Item	Scope Type	Site	3		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Physic	cal Quantities - Force, To	orque			רו, מומנט	כיול – גדלים פיזיקליים - כ
612	Α	P,T	Force calibration in tension, force measurement machine	כיול כח במתיחה, מכונות למדידת כח	[0.1 kN to 100 kN]	1.5 N/kN of verification force	ISO 7500-1 ASTM E4 Manufacturer instructions	Force load cell מתמר כת Calibration can be given in other units as required. 1 N/kN = 0.1%
613	A	Т	Force calibration in tension, material testing machine	כיול כח במתיחה, מכונות למדידת כח	[0.1 kN to 500 kN]	2.0 N/kN of verification force		
614 615		P;T P;T	Force calibration in compression, material testing machine	כיול כח בלחיצה, מכונות למדידת כח	[0.1 kN to 1 MN] (1 MN to 2.3 MN]	2.0 N/kN of verification force 2.4 N/kN of verification force		כולל כיול מכונות בדיקה לפי דרישות תקן ישראלי 26 חלק 4.1
616	A	P;T	Force calibration in tension and compression, push pull force measurement machine	כיול כח בלחיצה ומתיחה מכונות למדידת כוח	(0.005 N to 1.2 kN]	1.0 N/kN of verification force		משקולות
617 618		P P	Force calibration in tension and compression, Proving devices	כיול כח בלחיצה ומתיחה תאי (טבעות ) כוח	[0.005 N to 1.2 kN] [1 kN to 20 kN]	0.5 N/kN of verification force 0.7 N/kN of verification force	ISO 376 Euramet cg-4	משקולות , מתמר כח
619 620		P P	Force calibration in compression, Proving devices	כיול כח בלחיצה תאי (טבעות) כוח	[20 kN to 1 MN] [1 MN to 2.3 MN]	1.0 N/kN of verification force 2.0 N/kN of verification force		

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Physic	cal Quantities - Force, To	orque			ח, מומנט	כיול – גדלים פיזיקליים - כ
621	A	P	Force calibration in tension, Proving devices	כיול כח במתיחה תאי (טבעות) כוח	[20 kN to 100 kN]	1.0 N/kN of verification force		
622	A	P	Torque	מומנט	[0.1 Nm to 25 Nm]	1.0% OR	ISO 6789	מתמרי מומנט
623	3 A	Р	Torque wrenches and drivers	ידית מומנט ,מברגת מומנט	[25 Nm to 1000 Nm]	0.5% OR		קורות כיול ומשקולות Calibration can be given in other units as required
624	A	P	Torque Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	[0.1 Nm to 1000 Nm]	0.07% OR	BS 7882 Euramet cg-14	OR – Of Reading OR – Of Reading
625	S A	Т	Torque  Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	[0.1 Nm to 50 Nm]	0.2% OR		קורות כיול ומשקולות
626	5 A	Т	Torque Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	(50 Nm to 1000 Nm]	1% OR		מתמרי מומנט OR – Of Reading

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Calibro	ation –	Physic	al Quantities - Humidity				מות	כיול – גדלים פיזיקליים - ל
			Relative humidity	לחות יחסית	0 °C to 10 °C		ASTM-E-104-85	Chilled mirror hygrometer.
627	A	P	RH meters		(5% rh to 50%] rh	1.0 % rh	NIS 19	היגרומטר מד נקודת טל.
628	A	P	RH data loggers		(50% rh 80%] rh	1.4 % rh	OIML R121	Humidity and temperature controlled chamber.
			RH probes				Manufacturer instructions	תא מבוקר לחות וטמפרטורה.
			RH transducers	לחות יחסית	10 °C to 45 °C			,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,
629	A	P	לחות יחסית		(5% rh to 50%] rh	0.8 % rh		
630	A	P	מדי לחות		(50% rh 80%] rh	1.1 % rh		
631	A	P	רגשי לחות		(80% rh 95%] rh	1.3 % rh		
			מתמרי לחות	לחות יחסית	45 °C to 60 °C			
632	A	P	אוגרי נתונים		(5% rh to 50%] rh	0.8 % rh		
633	A	P			(50% rh to 80%] rh	1.0 % rh		
			Relative humidity	לחות יחסית	0 °C to 10 °C			Humidity sensors,
634	A	Т	RH probes		[5% rh to 80%] rh	2.0 % rh		Humidity and temperature controlled Calibrator
			RH chambers RH meters	לחות יחסית	10 °C to 45 °C			
635	A	T	לחות יחסית	_	[5% rh to 95%] rh	2.0 % rh		
636			27, 07, 21,,,,,	לחות יחסית	45 °C to 60 °C			

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Calibra	ation –	Physic	al Quantities - Humidity				חות	כיול – גדלים פיזיקליים - ל
637	A	Т	רגשי לחות תאי לחת מדי לחות		[5% rh to 80%] rh	2.0 % rh		
			Relative humidity	לחות יחסית	23°C ± 2 °C			Salt solutions in ampoules as
638	Α	P;T	RH probes		11.3% rh	0.5% rh		humidity standards.
639	A	P;T	לחוות יחסית		35% rh	0.7% rh		
640	A	P;T	רגשי לחות		50% rh	1.1% rh		
641	A	P;T			75% rh	1.5% rh		
642	Α	P;T			80% rh	1.5% rh		
643	A	P;T			95% rh	1.6% rh		
644	A	P;T	Dew point	נקודת טל	$[-40  {}^{0}\text{C} \text{ to } -30]  {}^{0}\text{C}$	0.35 °C		Chilled mirror hygrometer
645	A	P;T	RH meters		$[-30  {}^{0}\text{C to} + 50]  {}^{0}\text{C}$	0.2 °C		היגרומטר מד נקודת טל.
646	A	P;T	RH transducers לחוות יחסית מדי לחות		(50 °C to 60] °C	0.25 °C		
			מתמרי לחות					

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	tion –	Physic	al Quantities - Mass	_			<i>סה</i>	כיול – גדלים פיזיקליים - מ
647 648 649 650 651 652 653 654 655 656 657 658 659 660 661	A A A A A A A A A A A A A A A A A A A	Physics P P P P P P P P P P P P P P P P P P P	Mass Weights	מסה משקולות	20000 g 10000 g 5000 g 2000 g 1000 g 500 g 200 g 1000 g 500 g 200 g 100 g 50 g 20 g 10 g 50 g 20 g 10 g 50 g 20 g 10 g 50 g	40 mg 5.1 mg 2.9 mg 0.63 mg 0.50 mg 0.35 mg 0.080 mg 0.049 mg 0.030 mg 0.021 mg 0.020 mg 0.0081 mg 0.0063 mg 0.0054 mg 0.0044 mg 0.0035 mg	OIML R 111-1 OIML R 52 ASTM-E-617	מאוני השוואה Calibration can be given in other units as required. Intermediate value can be calibrated with an uncertainty interpolated from the next higher and lower values in the table.

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Calibra	ation –	Physica	al Quantities - Mass			מסה	כיול – גדלים פיזיקליים - ו
663	A	P		0.1 g	0.0029 mg		
664	A	P		0.05 g	0.0026 mg		
665	A	P		0.02 g	0.0025 mg		
666	A	P		0.01 g	0.0020 mg		
667	A	P		0.005 g	0.0020 mg		
668	A	P		0.002 g	0.0020 mg		
669	A	P		0.001 g	0.0020 mg		
670	A	P		[0.5 g to 200 g]	0.1 mg		מאזני השוואה
671	A	P		(200 g to 1 kg]	0.5 mg		
672	A	P		(1 kg to 5 kg]	20 mg		
673	A	P		(5 kg to 10 kg]	30 mg		
674	A	P		(10 kg to 29 kg]	60 mg		

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Physic	cal Quantities - Mass				<i>סה</i>	כיול – גדלים פיזיקליים - מ
675 676 677 678	A A A	P;T P;T P;T P;T P;T	Non automatic weighing instruments Resolution 0.001 mg and less	מאזניים לא אוטומטיים כושר הפרדה 0.001 mg מוך. נמוך.	(Up to 10 mg] (10 mg to 500 mg] (500 mg to 2 g] (2 g to 5 g] (5 g to 20 g]	2.5 μg 5 μg 7 μg 10 μg 25 μg	OIML R76 Manufacturer instructions	1. Uncertainties depend on the performance of the weighting machine under calibration. 2. Available weights are: OIML Class E2 from 1 mg
680	A	P;T			(20 g to 50 g]	30 μg		to 2 kg, OIML Class F1 from 1 mg
681 682 683	A	P;T P;T P;T	Non automatic weighing instruments Resolution 0.01 mg	מאזניים לא אוטומטיים כושר הפרדה.0.01 mg	(Up to 5 g] (5 g to 50 g] (50 g to 250 g]	15 μg 40 μg 80 μg		to 5 kg, OIML Class F2 from 1 mg to 5 kg, OIML Class M1 from 1 mg
684 685 686	A	P;T P;T P;T	Non automatic weighing instruments Resolution 0.1 mg	מאזניים לא אוטומטיים כושר הפרדה 0.1 mg	(Up to 50 g] (50 g to 250 g] (250 g to 520 g]	0.1 mg 0.2 mg 0.4 mg		to 20 kg, OIML Class M2 from 5 kg to 20 kg, test weights 2 × 500 kg.
687 688 689 690	A A	P;T P;T P;T P;T	Non automatic weighing instruments Resolution 0.001 g  Non automatic weighing instruments Resolution 0.01 g	מאזניים לא אוטומטיים כושר הפרדה g 0.001 מאזניים כושר הפרדה.g	(Up to 620 g] (620  g - 2  kg] (Up - 5.1  kg] (5.1  kg - 12.1  kg]	2 mg 3 mg 0.01 g 0.02 g		OIML Class E1 weights can be provided on demand.

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Physic	cal Quantities - Mass				מסה	כיול – גדלים פיזיקליים - נ
691	A	P;T	instruments	מאזניים לא אוטומטיים	(0 to 8.1 kg]	0.1 g		
692	A	P;T		Resolution 0.1 g	0.1	(8.1 kg to 32 kg]	0.2 g	
693	A	P;T		כושר הפרדה 0.1 g	(32 kg to 64 kg]	0.4 g		
694	A	P;T	Non automatic weighing	מאזניים לא אוטומטיים	(Up to 50 kg]	1 g		
695	A	P;T	Resolution 0.001 kg	כושר הפרדה 0.001 kg	(50 kg to 150 kg]	2 g		
696	A	P;T	Non automatic weighing	מאזניים לא אוטומטיים	(Up to 200 kg]	10 g		
697	A	P;T	Resolution 0.01 kg	כושר הפרדה 0.01 kg	(200 kg to 500 kg]	20 g		
698	A	P;T	Non automatic weighing	מאזניים לא אוטומטיים	(Up 0 to 1000 kg]	0.1 kg		
699	A	P;T	instruments Resolution 0.1 kg	כושר הפרדה 0.1 kg	(1000 kg to 2000 kg]	0.2 kg		
700	A	P;T	Non automatic weighing instruments	מאזניים לא אוטומטיים	(Up to 10000 kg]	0.5 kg		
			Resolution 0.5 kg	כושר הפרדה 0.5 kg				

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibra	ation –	-Physic	cal Quantities - Pressure			ל - גדלים פיזיקליים –לחץ			
701	A	P;T	Pneumatic pressure,	לחץ פניאומאטי, יחסי	[-1.25 kPa to 1.25 kPa]	0.7 Pa/kPa OR + 0.05 Pa	OIML-R 101	Druck 610LP	
			Gauge.	מדידי לחץ פניאומאטיים			Euramet cg 17	1  Pa/kPa = 0.1%	
			Pressure indicating instruments and gauges	לחץ הפרשי			Manufacturer instructions		
			Differential pressure					D 1 1 50077	
702	A	P Pneumatic pressur Absolute.	Pneumatic pressure Absolute.	לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים	[1.6 kPa to 7 MPa]	0.10 Pa/kPa OR + 1 Pa		Budenberg 580H Ruska 2465-754	
			Pressure indicating instruments and gauges			0.70 7 6 7 7 7 7 8			
703	A	P	Pneumatic pressure,	לחץ פניאומאטי, יחסי	[1.6 kPa to 7 MPa]	0.10 Pa/kPa OR + 0.35 Pa		Ruska 2465-754	
			Gauge.	מדידי לחץ פניאומאטיים					
			Pressure indicating instruments and gauges						
704	A	P	Pneumatic pressure,	לחץ פניאומאטי	[1.6 kPa to 7 MPa]	0.10 Pa/kPa OR + 0.35 Pa	Euramet cg 3	Ruska 2465-754	
			Dead weight tester.	כיול שטח אפקטיבי של בוכנת			Manufacturer instructions	Dead weight tester to be	
			Effective area of pneumatic dead weight tester piston	מאזני לחץ פניאומאטיים				supplied with its mass set Calibration by means of cross float method	
705	A	P	Hydraulic pressure,	לחץ הידראולי	[0.6 MPa to 121 MPa]	0.20 Pa/kPa	OIML-R 101	DH-Budenberg 580HX	
			(gauge)	מדידי לחץ			Euramet cg 17 Manufacturer instructions		
			Pressure indicating instruments and gauges				Translated instructions		

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The certificate attached is an integral part of the schedule and is numbered identically המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המפרה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המפרה הנספח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המפרח הנספח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המפרח הנספח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המפרח הנספח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המפרח הנספח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח הנספח המפרח הנספח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המפרח המצורפת המ

### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	libration – Physical Quantities - Pressure						<i>בחץ</i>	כיול - גדלים פיזיקליים –י
706	A	P	Hydraulic pressure, Dead weight tester. Effective area of hydraulic dead weight tester piston	לחץ הידראולי כיול שטח אפקטיבי של בוכנת מאזני לחץ הידראוליים	[0.6 MPa to 121 MPa]	0.20 Pa/kPa	Euramet cg 3 Manufacturer instructions	DH-Budenberg 580HX Dead weight tester to be supplied with its mass set Calibration by means of cross float method
707	A	Т	Pneumatic pressure Absolute Pressure indicating instruments and gauges	לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים	[1.6 kPa to 0.7 MPa]	1.5 Pa/kPa	OIML-R 101 Euramet cg 17 Manufacturer instructions	Druck 610 Druck 603 Druck 104
708	A	Т	Pneumatic pressure Gauge Pressure indicating instruments and gauges	לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים	[1.6 kPa to 7 MPa]	1.0 Pa/kPa		
709	A	Т	Hydraulic pressure (gauge) Pressure indicating instruments and gauges	לחץ הידראולי מדידי לחץ	[0.6 MPa to 70 MPa]	1.0 Pa/kPa		

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instr	ument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibrati	on – Pl	hysical	Quantities - Temperature		, , , , , , , , , , , , , , , , , , , ,		ומפרטורה	כיול – גדלים פיזיקליים - נ
710	A	P	Liquid in glass thermometers	תרמומטרים נוזל בזכוכית	[-80 °C to -30 °C]	0.15 °C	ISO 1770	אמבטיות כיול
711	A	P			(- 30 °C to 0 °C]	0.1 °C	ISO 1771	תרמומטר אב PRT
							ISO 386	
712	A	P			0 °C	0.01 °C	JIS 7411	
713	Α	P			(0 °C to 250 °C]	0.08 °C	JIS 7412	
71.4		D.			(250.00 . 550.00)	0.500	JIS 7542	
714	Α	P			(250 °C to 550 °C]	0.5°C	ASTM E563	
715	A	T			[-40 °C to 150 °C]	1.0 °C	ASTM E77	
716	A	Т			0 ℃	0.05 ℃	BS 593	
/10	A	1			0 C	0.03 C	BS 1704	
717	A	T			(150 °C to 250 °C]	2.0 °C		
718	A	P	PRT	גששי טמפרטורה התנגדות	-196 ℃	0.02 °C	ASTM-E-1137	Liquid nitrogen
719	A	P	Measurement by comparison		[- 80 °C to 250 °C]	0.02 ℃	ASTM-E-644	PRT may calibrated with its
/19	Α	1			[- 80 C to 230 C]	0.02 C	IEC 751	indicator. The uncertainty will be dependent on the
720	A	P			(250 °C to 550 °C]	0.05 ℃	ITS-90	indicator performance.
721	A	P			(550 °C to 661 °C]	0.3 ℃	Manufacturer instructions	
722	A	P			0.01 °C	0.006 °C		By WTP
723	A	T	PRT	גששי טמפרטורה התנגדות	-196 ℃	0.1 ℃		Liquid nitrogen
724	A	Т	Measurement by comparison		[-80 °C to -40 °C]	0.3 ℃		
725	A	Т			[- 40 °C to 140 °C]	0.1 ℃		
726	A	T			(140 °C to 250 °C]	0.3 ℃		
727	A	Т			(250 °C to 650 °C]	0.5 °C		

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The certificate attached is an integral part of the schedule and is numbered identically המעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח The certificate attached is an integral part of the schedule and is numbered identically

### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibrati	on – Ph	ysical	Quantities - Temperatur	e	ביול – גדלים פיזיקליים - טמפרטורה			
728 729 730 731 732 733 734 735	A A A A A	P P P T T	TC base metal  Measurement by comparison	צמדים תרמיים מתכות בסיסיות	-196 °C  [- 80 °C to 250 °C]  (250 °C to 550 °C]  (550 °C to 1100 °C]  -196 °C  [- 80 °C to -40 °C]  [- 40 °C to 250 °C]  (250 °C to 550 °C]	0.14 °C 0.14 °C 0.4 °C 1 °C 0.3 °C 0.5 °C 0.5 °C	ASTM-E-230 ASTM-E-220 ITS-90 Manufacturer instructions	Liquid nitrogen TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
736	A	Т			(550 °C to 1100 °C]	1.5 ℃		
737 738 739 740 741	A A A A	P P T T	TC noble metal Measurement by comparison	צמדים תרמיים מתכות אצילות	[- 50 °C to 550 °C] (550 °C to 1100 °C] [- 50 °C to 250 °C] (250 °C to 550 °C] (550 °C to 1100 °C]	0.4 °C 1 °C 0.5 °C 0.7 °C 1.5 °C	ASTM-E-230 ASTM-E-220 ITS-90 Manufacturer instructions	TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
742	A	P;T	Freezing chambers Including uniformity	מקפיאים כולל בדיקת אחידות	[-80 °C to -50 °C]	1 °C	DKD-R-5-7 Manufacturer instructions	TC, PRT, Data logger

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibrati	on – Pl	hysical	Quantities - Temperature	·	כיול – גדלים פיזיקליים - טמפרטורה			
743	A	P;T	Freezers, Incubators, Autoclaves Including uniformity	מקפיאים, אינקובטורים אוטוקלבים כולל בדיקת אחידות	[-50 °C to 151 °C]	0.5 ℃	DKD-R-5-7 DIN 12880 Manufacturer instructions	TC, PRT, Data logger
744	A	P;T	Furnaces	תנורים	[50 °C to 300 °C]	0.7 °C	DKD-R-5-7 DIN 12880 Manufacturer instructions	TC, PRT, Data logger
745	A	P;T	Including uniformity	כולל בדיקת אחידות	(300 °C to 550 °C]	1 °C		
746	A	P;T			(550 °C to 1100 °C]	2.5 ℃		
747	A	P;T	Bathes	אמבט	[-196 °C to 251 °C]	0.03 °C	Manufacturer instructions	SPRT, PRT
748	A	P;T	Including uniformity	כולל בדיקת אחידות	(251 °C to 550 °C]	0.09 ℃		
749	A	P	Dry block calibrator	תנור בלוק יבש	[-110 °C to 300 °C]	0.05 ℃	EURAMET cg-13	PRT
750	A	P			(300 °C to 650 °C]	0.3 °C	Manufacturer instructions	
751	A	P;T	Tube furnace	תנור כיול צינורי	[300 °C to 660 °C]	0.2 ℃	Manufacturer instructions	
752	A	P;T	Including uniformity	כולל בדיקת אחידות	(660 °C to 1100 °C]	1.2 ℃		
753	A	P;T	Temperature indicators, controllers, recorders and simulators for the resistance sensors	מדי, רשמי ומדמי טמפרטורה עבור מדי התנגדות	-200 °C to 800 °C	0.01 ℃	EURAMET cg-11 Manufacturer instructions	Calibration by means of electrical calibration,
754	A	P	Temperature indicators, controllers, recorders and	מדי, רשמי ומדמי טמפרטורה עבור צמדים תרמיים מתכות בסיסיות	-200 °C to 1380 °C	0.2 °C	EURAMET cg-11 Manufacturer instructions	Calibration by means of electrical calibration,
755	A	T	simulators for the base metal thermocouples		-200 °C to 1380 °C	0.4 °C		including cold junction compensation

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibratio	Calibration – Physical Quantities - Temperature					כיול – גדלים פיזיקליים - טמפרטורה			
756	A	P	Temperature indicators, controllers, recorders and simulators for the noble	מדי, רשמי ומדמי טמפרטורה עבור צמדים תרמיים מתכות אצילות	0 °C to 500 °C	0.5 °C	EURAMET cg-11 Manufacturer instructions	Calibration by means of	
757	A	P			500 °C to 1800 °C	0.3 °C		electrical calibration, including cold junction	
758	A	Т	metal thermocouples		0 °C to 500 °C	0.9 °C		compensation	
759	A	T			500 °C to 1800 °C	0.6 °C			
760	A	P	Temperature, Infrared Thermometers,	T. C. 177	[35 °C to 100 °C]	0.6 °C	ASTM E2847 Manufacturer instructions המלצות יצרן	IR Calibrator	
761	A	P		מדי טמפרטורת קרינה	(100 °C to 200 °C]	1.0 °C			
762	A	P			(200 °C to 350 °C]	1.7 °C			
763	A	P			(350 °C to 500 °C]	2.5 °C			

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Small	(up to 2L) Volume Volu	metric Instruments	ול – כיול מכשירים וולומֶטְרִיים – נפחים קטנים עד 2 ליטר			
764 765		P P	Liquid volume, Piston-operated volumetric apparatus	נפח נוזלים כיול מכשירים וולומטריים בהנע בוכנה	Nominal value 1 µl 2 µl	0.030 μl 0.040 μl	ISO 8655- Part 1,2,3,4,5,6 ISO/TR 20461 Manufacturer instructions	POVA מתקן נפח מופעל בוכנה Intermediate volumes may be calibrated with uncertainty as for the higher volume value
766		P			5 μl	0.050 μ1		
767 768		P P			10 μl 20 μl	0.060 μl 0.080 μl		
769		P			50 μl	0.21 μ1		
770 771		P P			100 μl 200 μl	0.27 μl 0.72 μl		
772	A	P			500 μl	1.3 μl		
773	A	P			1000 μ1	1.8 μl		
774	A	P			2000 μ1	5.4 μl		
775		P			5000 μ1	9.6 μ1		
776 777		P P			10000 μl 20000 μl	15 μl 20 μl		
778		P			25000 µl	25 μl		
779	A	P			50000 μ1	35 μl		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

Date of issue 13.05.2016 Version No. 1

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